

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) 46955.20		Application Number 10/519349			
				Applicant(s) Hillenbrand, et al. / Customer Number 041068					
				Filing Date 27 December 2004 (371 date)		Group Art Unit 2884 Not Yet Assigned			
U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
/CI/	AA	6408123	18 Jun 2002	Kuroda, et al.			9 Nov 2000		
/CI/	AB	5602820	11 Feb 1997	Wickramasinghe, et al.			24 Aug 1995		
/CI/	AC	4947034	7 Aug 1990	Wickramasinghe, et al.			28 Apr 1989		
U.S. PATENT APPLICATION PUBLICATIONS									
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
FOREIGN PATENT DOCUMENTS									
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES NO		
/CI/	AD	DE 10035134 A1	14 Feb 2002	Germany			✓		
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>									
/CI/	AE	S. KLABITZER; "Generation of optical contrast in insulating materials by irradiation with focused ion beams", Applied Physics A, Vol. 71, pp 565-569.							
/CI/	AF	R. HILLENBRAND, et al.; "Material-specific mapping of metal/semiconductor/dielectric nanosystems at 10 nm resolution by backscattering near-field optical microscopy", Applied Physics Letters, Vol. 80 Number 1, (2002), pp25-27.							
EXAMINER /Carolyn Igyarto/				DATE CONSIDERED 11/12/2007					
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*EXAMINER INITIAL	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
/CI/	AG	R. HILLENBRAND, et al.; "Complex Optical Constants on a Subwavelength Scale", Physical Review Letters, Vol. 85, No. 14, 2000, pp 3029-3032.
/CI/	AH	Y. MARTIN, et al.; "Optical data storage read out at 256 Gbits/in.2", Applied Physics Letters, Vol. 71, 1997, pp 1-3.
/CI/	AI	B. KNOLL, et al.; "Infrared conductivity mapping for nanoelectronics", Applied Physics Letters; Vol. 77, No. 24, 2000, pp 3980-3982.
/CI/	AJ	B. KNOLL, et al.; "Near-field probing of vibrational absorption for chemical microscopy", Nature, Vol. 399, 1999, pp 134-136.
/CI/	AK	P.K. ARAVIND, et al.; "The effects of the interaction between resonances in the electromagnetic response of a sphere-plane structure; applications to surface enhanced spectroscopy", Surface Science, Vol. 124, 1983, pp 506-528.
/CI/	AL	B. KNOLL, et al.; "Enhanced dielectric contrast in scattering-type scanning near-field optical microscopy", Optics Communications, Vol. 182, No. 4-6, 2000, pp 321-328
/CI/	AM	F. KEILMANN, et al.; "Long-Wave-Infrared Near-Field Microscopy", physica status solidi, Vol. 215 ISS.1, 1999, pp 321-328.
/CI/	AN	T.R. JENSEN, et al.; "Nanosphere Lithography: Tunable Localized Surface Plasmon Resonance Spectra of Silver Nanoparticles", J. Phys. Chem. B, Vol. 104, No. 45, 2000, pp 10549-10556.
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/Carolyn Igyarto/		11/12/2007

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